

## **Sample Results Summary Sheet**

**Please return this form to the Curator for each allocated Sample**

**Sample ID:** RA-QD02-0062-1,2

PI: Tomoki Nakamura

**Type and date of analysis performed:**

XRD Jan/28/2011~ Feb/3/2011

FE-SEM, FE-EPMA Feb/19/2011~ Feb/28/2011

**Elements or phases identified:** (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)

XRD : OI, LPx, PI

## FE-SEM : OI, K-rich fd, Al

FE-EPMA : Si, Al, Fe, Mn, Mg, Na, P

**Contaminant phases identified:** (Al, SUS, carbon particles, etc.)

N/A

## **Sample handling:**

XRD

Attached to carbon fiber with resin.

FE-SEM, FE-EPMA

Exposed in atmosphere.

Polished by M cross

### C-coated (20 nm)

## **State of sample pre-analysis:**

Attached to carbon fiber with resin. (XRD)

## Polished section with resin embedded (FE-SEM, FE-EPMA)

#### **State of sample post-analysis:**

Attached to carbon fiber with resin. (XRD)

Polished section with resin embedded, C-coated (FE-SEM, FE-EPMA)

N<sub>2</sub> hold in sample holder.

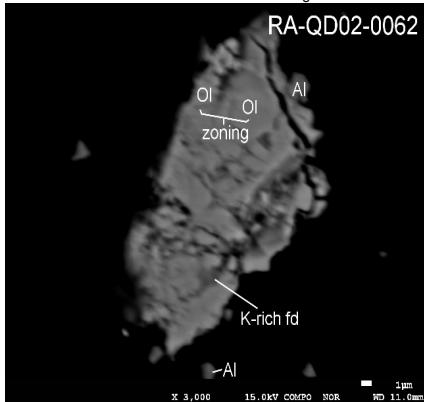
**Analysis data Notes:** (summary of the attached analysis data and/or images)

See attached sheets.

# RA-QD02-0062-1,2

Analysis S-XRD (polish) FE-SEM FE-EPMA  
Present status Putted butt with some SIMS spots

FE-SEM/BSE of 0062-1 0062-2 has no image



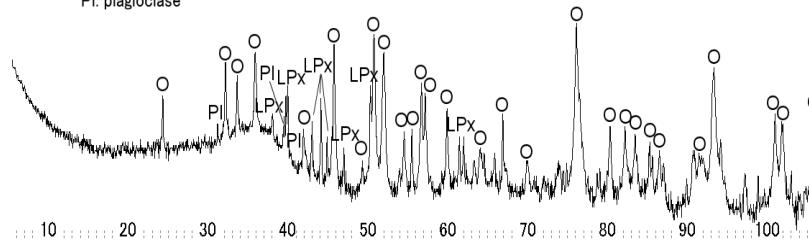
S-XRD

## Itokawa RA-QD02-0062-1 and 0062-2

O: olivine

LPx: low-Ca pyroxene

Pl: plagioclase



### FE-EPMA

wt%	Olivine n=1:Ol 1 sigma	LPx n=0 .Px 1 sigma:	HPx n=0 +Px 1 sigma:	Plagio n=0 Pl 1 sigma
SiO <sub>2</sub>	37.40	0.98		
TiO <sub>2</sub>	0.01	0.01		
Al <sub>2</sub> O <sub>3</sub>	0.05	0.09		
FeO	24.84	0.45		
MnO	0.46	0.03		
MgO	36.43	1.31		
CaO	0.01	0.01		
Na <sub>2</sub> O	0.02	0.03		
K <sub>2</sub> O	0.01	0.01		
Cr <sub>2</sub> O <sub>3</sub>	0.02	0.02		
NiO	0.02	0.03		
P <sub>2</sub> O <sub>5</sub>	0.07	0.07		
SO <sub>3</sub>	0.02	0.02		
Total	99.36	1.98		
SUM				

### Comment

Olivine (Fa#)

27.68 0.52

LPx(Fs#)

LPx(Wo#)

LPx(En#)

HPx(Fs#)

HPx(Wo#)

HPx(En#)

Pl(Or#)

Pl(An#)

Pl(Ab#)